





SID4 UV HR

UV WAVEFRONT SENSOR SENSITIVE DOWN TO 190 NM

Based on Phasics patented technology, the SID4 UV HR wavefront analyzer offers both an unrivalled high resolution (355x280 measurements points) and a high sensitivity (1 nm RMS) in the ultraviolet spectrum from 190 nm to 400 nm. Consequently, the SID4 UV HR is perfectly adapted for optical components characterization (used in lithography, semiconductor...) and surface inspection (lens and wafers...).

APPLICATIONS: Laser industry | Astronomy | Semiconductor | Aerospace

SPECIFICATIONS	
Wavelength range	190 - 400 nm
Aperture dimensions	13.84 x 10.89 mm²
Phase spatial resolution	38.88 µm
Phase & Intensity sampling	355 x 280
Resolution (Phase)	1 nm RMS
Accuracy (Absolute)	10 nm RMS
Frame rate	30 fps
Real-time processing frequency	3 fps (full resolution)*
Interface	CameraLink
Dimensions	78 x 88.1 x 70.8 mm ³
Weight	~ 575g
* with SID4 software	

